

<b>Notice of References Cited</b>	Application/Control No. 10/597,660		Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
	Examiner HIEN NGUYEN		Art Unit 3768	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,565,510	05-2003	Haider, Bruno Hans	600/437
*	B	US-2003/0083563	05-2003	Katsman et al.	600/407
*	C	US-2004/0153862	08-2004	Grellmann et al.	714/043
*	D	US-2003/0195424	10-2003	McMorrow et al.	600/439
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2002282251	10-2002	Japan	Cameron et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.